Abstracts

A membrane quadrant probe for R&D applications

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Membrane probes are known for their applications to production probing and their ability to integrate RF lines, matching networks and good power supply bypassing for known good die testing on-wafer. Nonetheless, they require die-specific design and are not reconfigurable. In this paper, we discuss a quadrant probe based on membrane technology which offers this alternative with lower loss than membrane probes and better DC bypassing capability than any other quadrant probe.

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